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| INFORMATION DISCLOSURE STATEMENT<br><br>PTO-1449 | Atty. Docket No.<br>ABE-026        | Serial No.<br>10/524,778 |
|  | Applicant:<br>Shigeru UMENO et al. |                          |
|  | Filing Date:<br>February 16, 2005  | Group:<br>2812           |

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|                    | DB |  |
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| Examiner: <i>S.M. Malik</i> | Date Considered: <i>07/20/07</i> |
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| <b>INFORMATION DISCLOSURE STATEMENT</b><br><br>PTO-1449 | Atty. Docket No.<br>ABE-026        | Serial No.<br>Not assigned |
|   | Applicant:<br>Shigeru UMENO et al. |                            |
|   | Filing Date:<br>February 16, 2005  | Group:<br>Not assigned     |

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| Examiner: <i>S. M. Malekzadeh</i> | Date Considered: <i>07/20/07</i> |
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| <p>INFORMATION DISCLOSURE STATEMENT</p> <p>PTO-1449</p> | <p>Atty. Docket No.</p> <p>ABE-026</p>        | <p>Serial No.</p> <p>Not assigned</p> |
|   | <p>Applicant:</p> <p>Shigeru UMENO et al.</p> |                                       |
|   | <p>Filing Date:</p> <p>February 16, 2005</p>  | <p>Group:</p> <p>Not assigned</p>     |

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| <p>Examiner:</p> <p><i>S. M. Nakagawa</i></p> | <p>Date Considered:</p> <p>07/20/07</p> |
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|  | Applicant:<br>Shigeru UMENO et al. |                          |
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|                    | UG |              |          |         |       |           |                            |

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